

# United States Patent [19]

Arnoux et al.

[11] Patent Number: **Des. 288,301**

[45] Date of Patent: **\*\* Feb. 17, 1987**

[54] **CLAMP-ON CURRENT PROBE**

4,518,913 5/1985 Jackson ..... 324/127

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[73] Assignee: **Construction d'Appareillage, Paris, France**

[\*\*] Term: **14 Years**

[21] Appl. No.: **620,891**

[22] Filed: **Jun. 15, 1984**

[30] Foreign Application Priority Data

Dec. 21, 1983 [FR] France ..... 834792

[52] U.S. Cl. .... **D10/79**

[58] Field of Search ..... **D10/46, 75-80, D10/103; 324/72.5, 127, 129, 156, 158 P**

[56] **References Cited**

### U.S. PATENT DOCUMENTS

D. 247,353 2/1978 Kuramoto ..... **D10/79**

D. 264,057 4/1982 Kuramoto ..... **D10/79**

### OTHER PUBLICATIONS

New Equipment Digest, 4/1980, p. 7-Phase Angle Meter at top center.

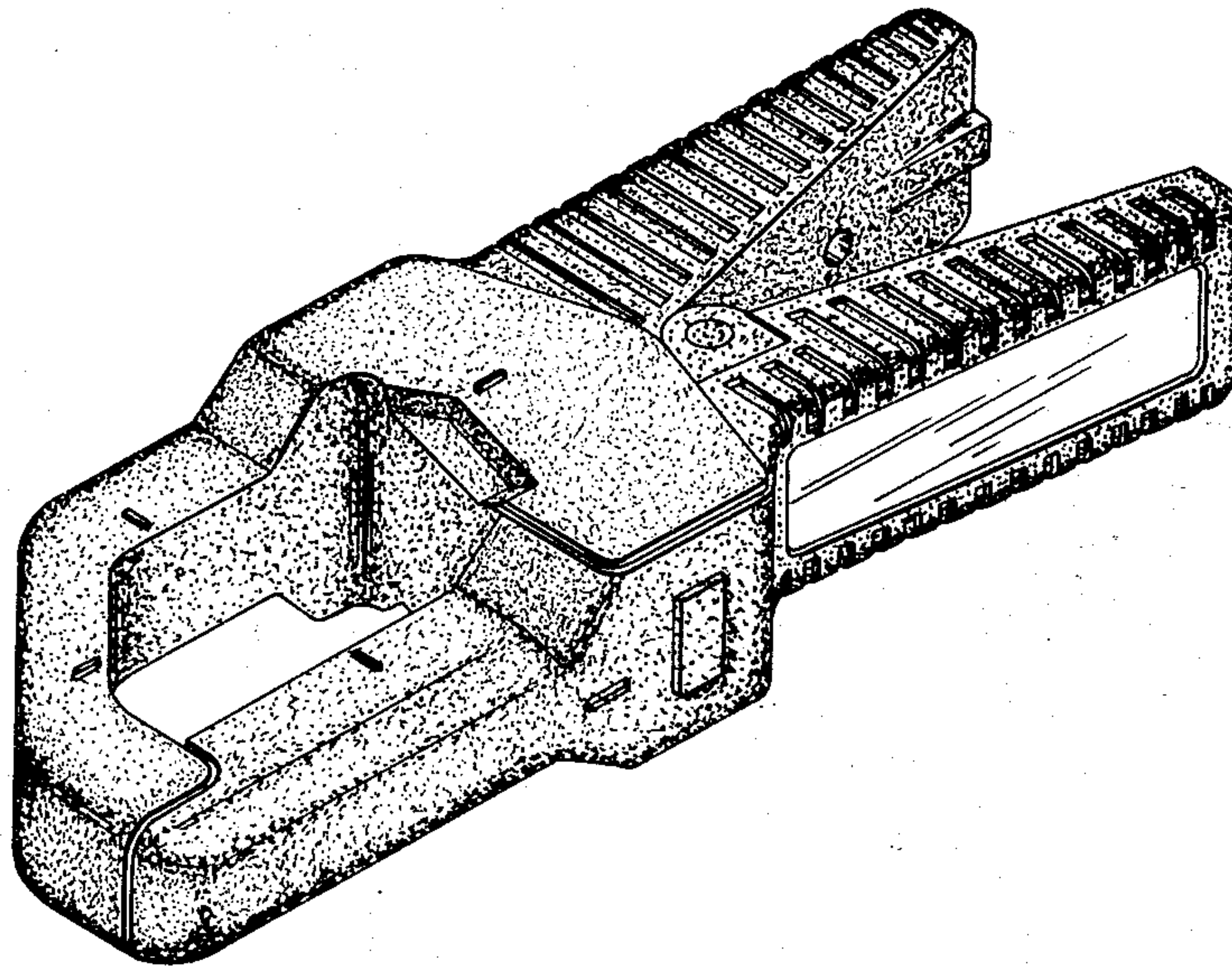
*Primary Examiner*—Louis S. Zarfaz  
*Attorney, Agent, or Firm*—Wolf, Greenfield & Sacks

[57] **CLAIM**

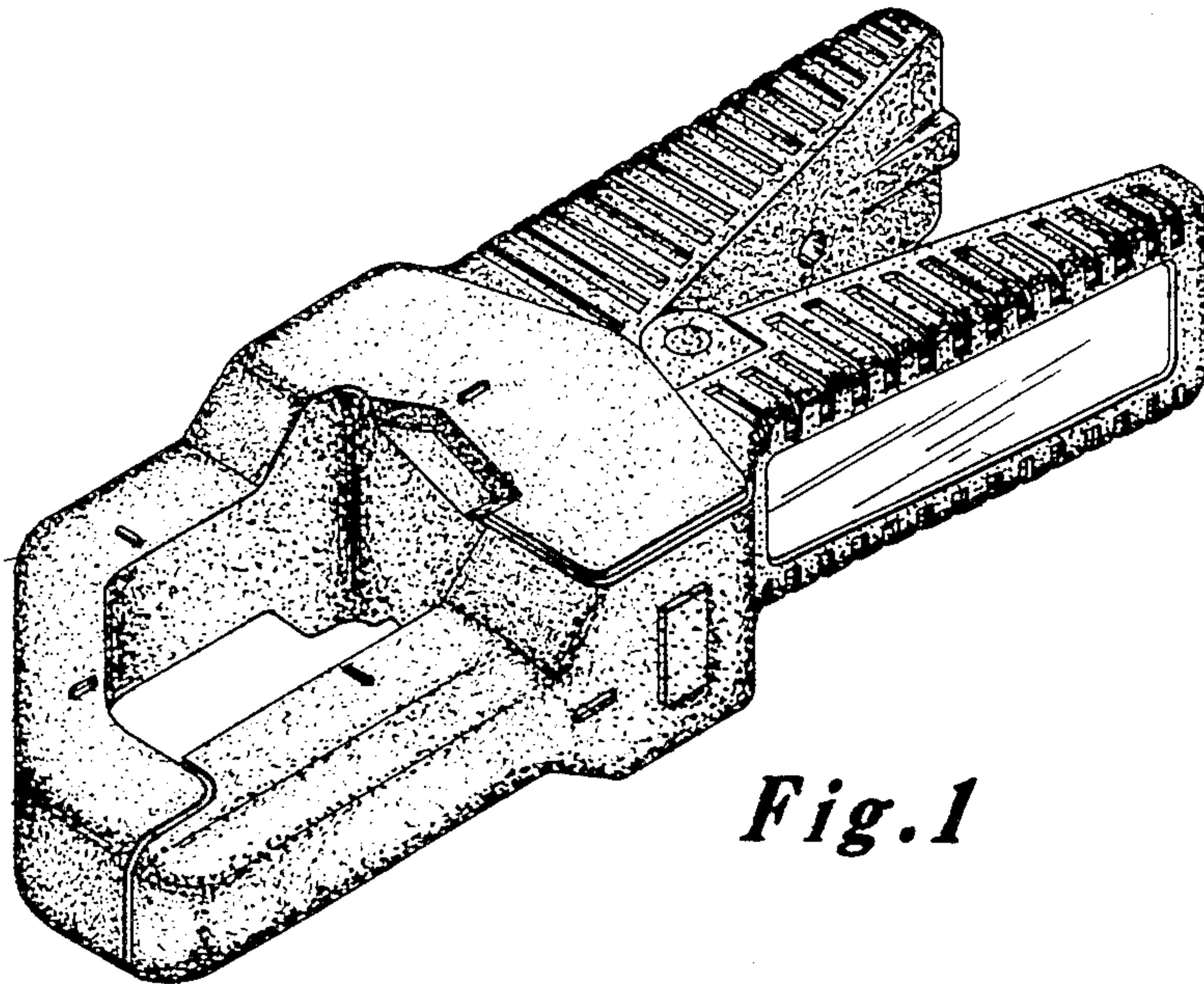
The ornamental design for a clamp-on current probe, as shown and described.

### DESCRIPTION

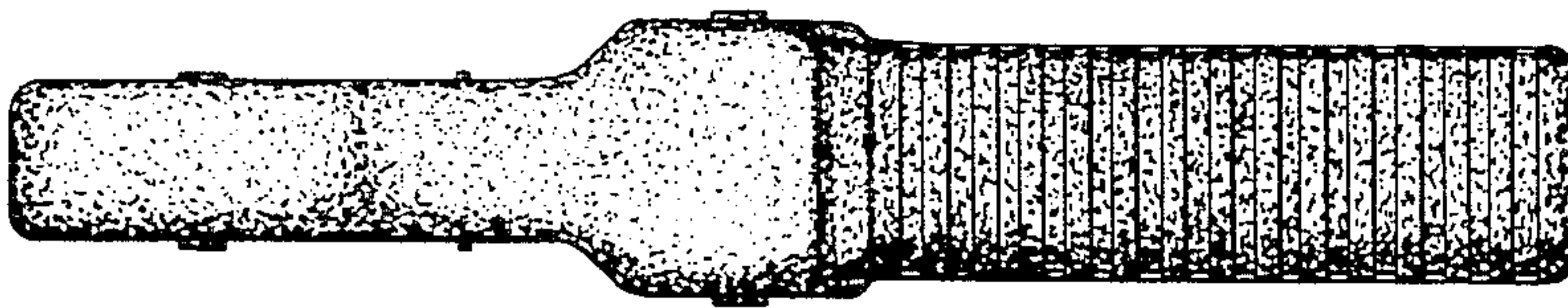
FIG. 1 is a perspective view of a clamp-on current probe showing our new design; FIG. 2 is a top plan view thereof; FIG. 3 is a left side elevational view thereof; FIG. 4 is a bottom plan view thereof; FIG. 5 is a rear elevational view thereof; and FIG. 6 is a front elevational view thereof.



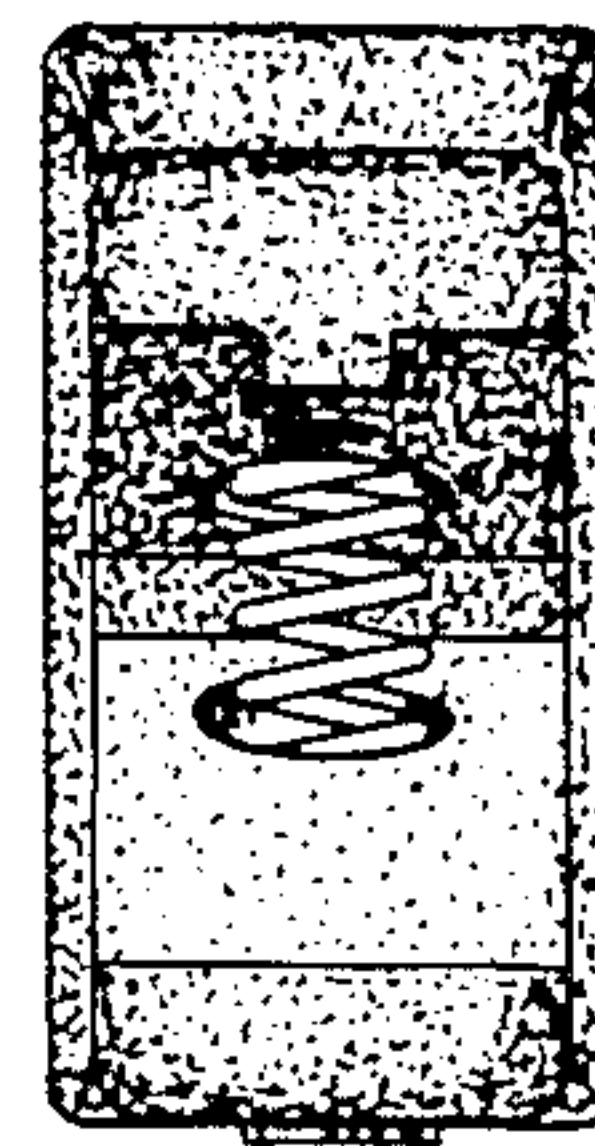




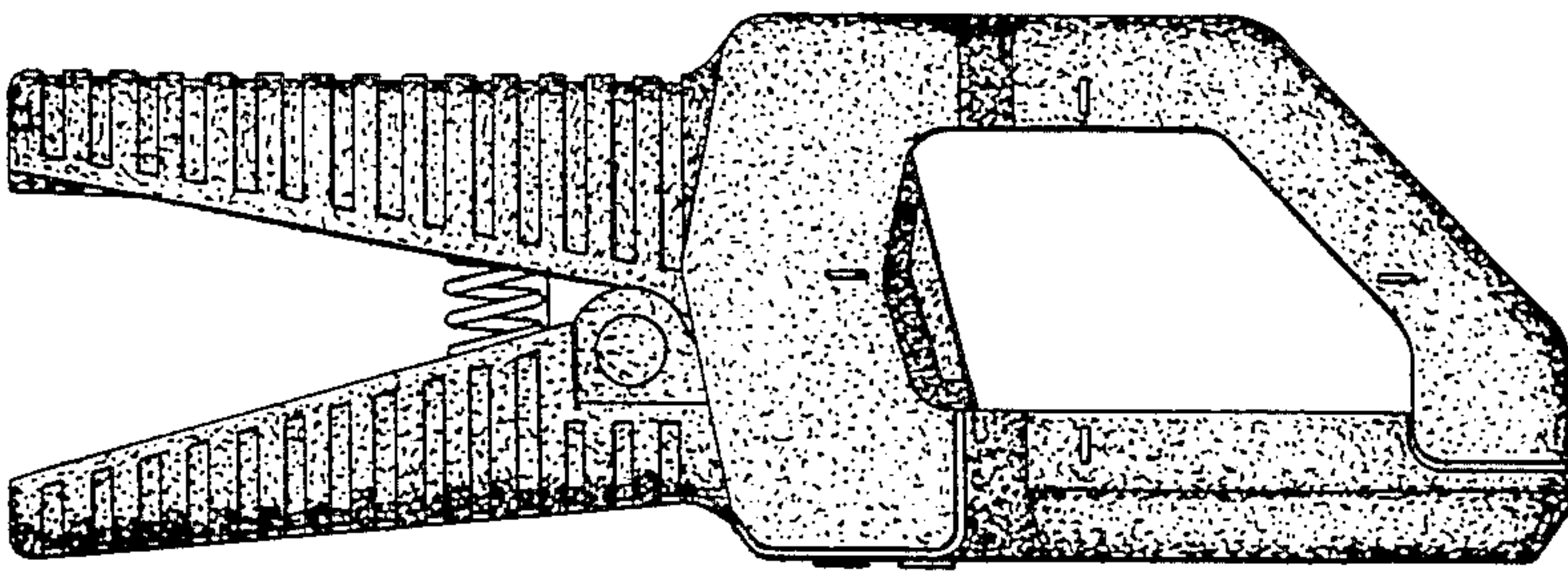
*Fig. 1*



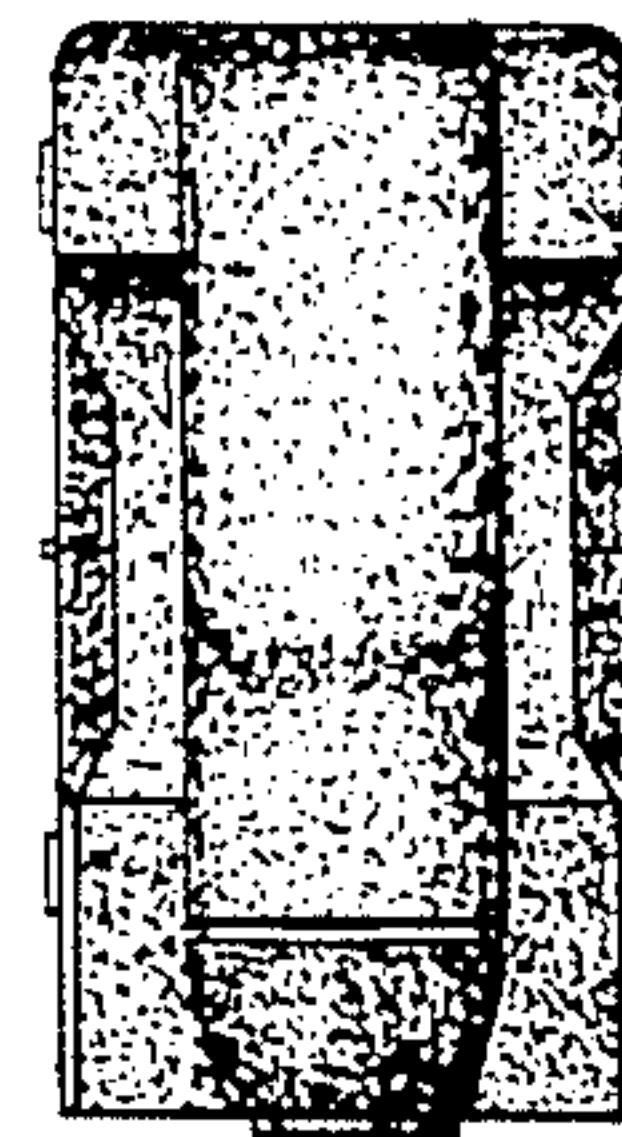
*Fig. 2*



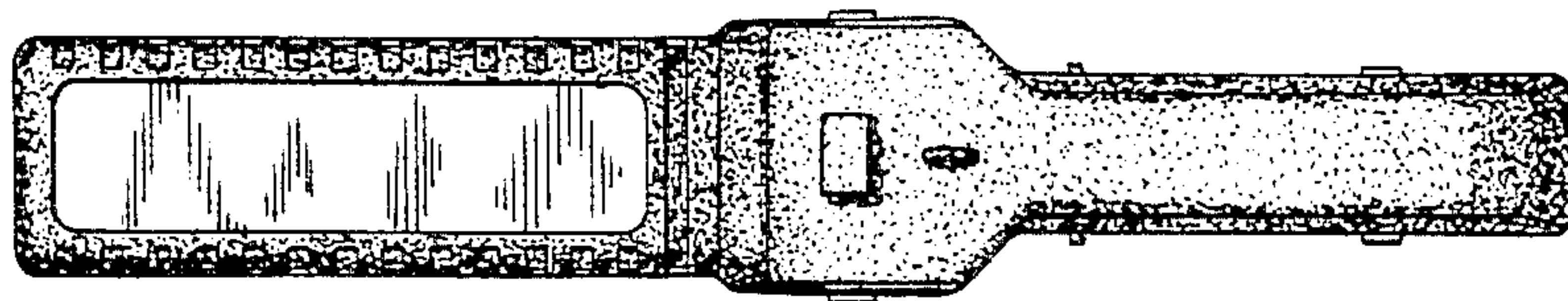
*Fig. 5*



*Fig. 3*



*Fig. 6*



*Fig. 4*